

Notice of References Cited	Application/Control No. 10/686,841	Applicant(s)/Patent Under Reexamination LAMBERTON ET AL.	
	Examiner Kevin M. Bernatz	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,802,753	10-2004	Ando et al.	445/6
	B	US-2003/0133224	07-2003	Minor et al.	360/125
	C	US-6,132,892	10-2000	Yoshikawa et al.	428/812
	D	US-4,933,026	06-1990	Rawlings et al.	148/311
	E	US-2005/0000444	01-2005	Hass et al.	118/723.0EB
	F	US-2003/0209295	11-2003	Cooper et al.	148/311
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Kong et al. (Mag. Conf, 2002, INTERMAG Europe 2002, Digest Papers)			
	V	Komuro et al. (J. Appl. Phys., 67(9), May 1990, 5126-5130)			
	W	Pan et al. (IEEE Trans. Mag., 37(4) 2001, 2284-2287)			
	X	Yu et al. (IEEE Trans. Mag., 38(5), 2002, 3030-3032) and Katada et al. (IEEE Trans. Mag., 38(5), 2002, 2225 - 2227)			
	Y				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.